FCC ID: 2AQI4-DS001

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]· $[\sqrt{f(GHZ)}]$ ≤ 3.0 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

WIFI:

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculatio n	SAR Exclusion threshold	SAR test exclusion
802.11b	2.412	8.5	7.08	8.5±1	9.5	8.91	<5	2.76834	3.00	YES
	2.437	9.1	8.13	8.5±1	9.5	8.91	<5	2.78264	3.00	YES
	2.462	9.2	8.32	8.5±1	9.5	8.91	<5	2.79688	3.00	YES
802.11g	2.412	7.3	5.37	8±1	9	7.94	<5	2.46728	3.00	YES
	2.437	7.8	6.03	8±1	9	7.94	<5	2.48003	3.00	YES
	2.462	7.9	6.17	8±1	9	7.94	<5	2.49272	3.00	YES
802.11n HT20	2.412	7.5	5.62	8±1	9	7.94	<5	2.46728	3.00	YES
	2.437	7.9	6.17	8±1	9	7.94	<5	2.48003	3.00	YES
	2.462	7.9	6.17	8±1	9	7.94	<5	2.49272	3.00	YES
802.11n HT40	2.422	7.4	5.50	8±1	9	7.94	<5	2.47239	3.00	YES
	2.437	7.8	6.03	8±1	9	7.94	<5	2.48003	3.00	YES
	2.452	7.8	6.03	8±1	9	7.94	<5	2.48766	3.00	YES

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For the max result: 2.79688 W/Kg ≤ 3.0, compliance with FCC's RF Exposure

Jason chen

Signature: Date: 2018-09-25

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